

MOS FIELD EFFECT TRANSISTOR 2SJ626

P-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

DESCRIPTION

The 2SJ626 is a switching device which can be driven directly by a 4.0 V power source.

The 2SJ626 features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

FEATURES

- 4.0 V drive available
- · Low on-state resistance

RDS(on)1 = 388 m Ω MAX. (VGS = -10 V, ID = -1.0 A)

 $R_{DS(on)2} = 514 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = -4.5 \text{ V, Ip} = -1.0 \text{ A)}$

RDS(on)3 = 556 m Ω MAX. (VGS = -4.0 V, ID = -1.0 A)

ORDERING INFORMATION

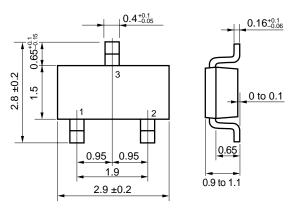
PART NUMBER	PACKAGE
2SJ626	SC-96 (Mini Mold Thin Type)

Marking: XN

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^{\circ}C$)

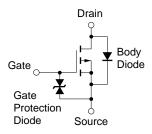
ABOOLO I E MAXIMOM KATINGO (I	1A - 23 0)		
Drain to Source Voltage (Vgs = 0 V)	Voss	-60	V
Gate to Source Voltage (Vps = 0 V)	Vgss	∓20	V
Drain Current (DC) (TA = 25°C)	ID(DC)	∓1.5	Α
Drain Current (pulse) Note1	D(pulse)	∓6.0	Α
Total Power Dissipation	P _{T1}	0.2	W
Total Power Dissipation Note2	P _{T2}	1.25	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to +150	°C

PACKAGE DRAWING (Unit: mm)



- 1 : Gate 2 : Source
- 3 : Drain

EQUIVALENT CIRCUIT



Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

2. Mounted on FR-4 board, $t \le 5$ sec.

Remark

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

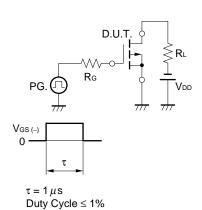
The information in this document is subject to change without notice. Before using this document, please confirm that this is the latest version. Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

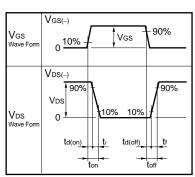


ELECTRICAL CHARACTERISTICS (TA = 25°C)

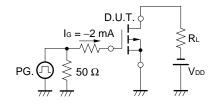
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	Vps = -60 V, Vgs = 0 V			-1.0	μΑ
Gate Leakage Current	Igss	V _G S = ∓20 V, V _D S = 0 V			∓10	μΑ
Gate to Source Cut-off Voltage	V _{GS(off)}	$V_{DS} = -10 \text{ V}, I_{D} = -1.0 \text{ mA}$	-1.5	-2.1	-2.5	V
Forward Transfer Admittance	y fs	V _{DS} = -10 V, I _D = -1.0 A	1.0	2.5		S
Drain to Source On-state Resistance	RDS(on)1	Vgs = -10 V, ID = -1.0 A		310	388	mΩ
	RDS(on)2	V _{GS} = -4.5 V, I _D = -1.0 A		385	514	mΩ
	RDS(on)3	Vgs = -4.0 V, ID = -1.0 A		417	556	mΩ
Input Capacitance	Ciss	V _{DS} = -10 V		255		pF
Output Capacitance	Coss	V _G S = 0 V		45		pF
Reverse Transfer Capacitance	Crss	f = 1.0 MHz		17		pF
Turn-on Delay Time	t d(on)	$V_{DD} = -30 \text{ V}, \text{ ID} = -1.0 \text{ A}$		17		ns
Rise Time	t r	V _{GS} = -10 V		29		ns
Turn-off Delay Time	td(off)	$R_G = 10 \Omega$		92		ns
Fall Time	t f			65		ns
Total Gate Charge	Q _G	VDD = -48 V		8.2		nC
Gate to Source Charge	Qgs	V _{GS} = -10 V		1.3		nC
Gate to Drain Charge	Q _{GD}	I _D = −1.5 A		2.2		nC
Body Diode Forward Voltage	V _{F(S-D)}	I _F = 1.5 A, V _G s = 0 V		0.86		V

TEST CIRCUIT 1 SWITCHING TIME



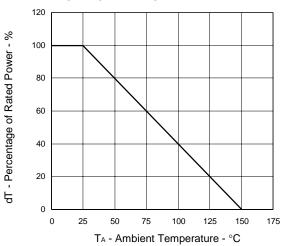


TEST CIRCUIT 2 GATE CHARGE

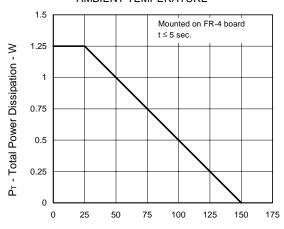


TYPICAL CHARACTERISTICS (TA = 25°C)

DERATING FACTOR OF FORWARD BIAS SAFE OPERATING AREA

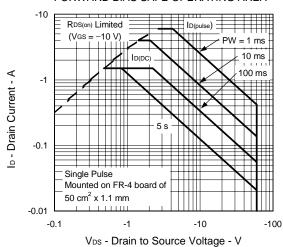


TOTAL POWER DISSIPATION vs. AMBIENT TEMPERATURE

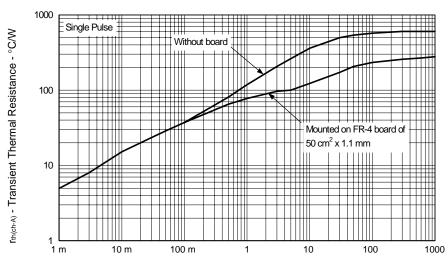


T_A - Ambient Temperature - °C

FORWARD BIAS SAFE OPERATING AREA



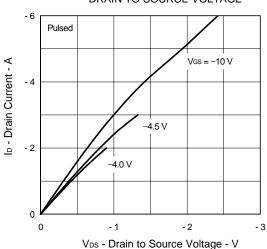
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



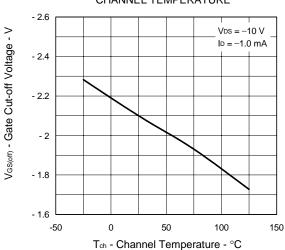
PW - Pulse Width - s

3

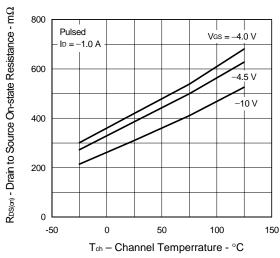
DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE



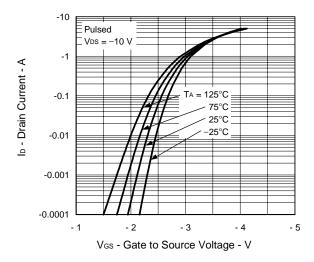
GATE CUT-OFF VOLTAGE vs. CHANNEL TEMPERATURE



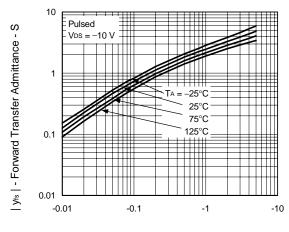
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



FORWARD TRANSFER CHARACTERISTICS

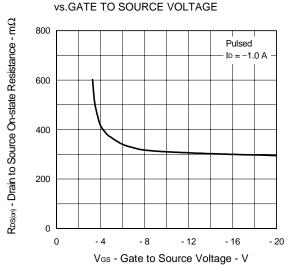


FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT

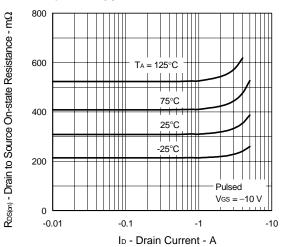


DRAIN TO SOURCE ON-STATE RESISTANCE

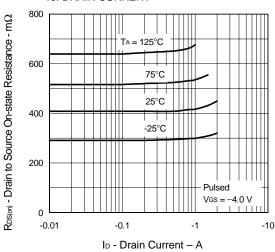
ID - Drain Current - A



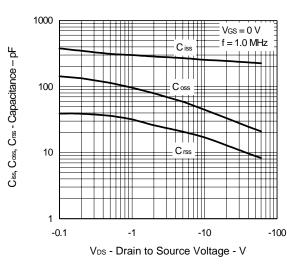
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



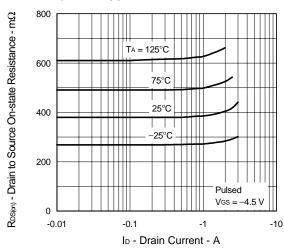
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



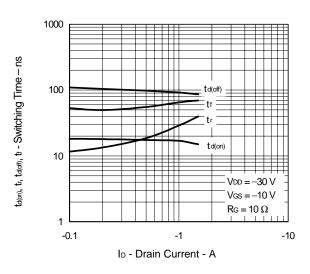
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



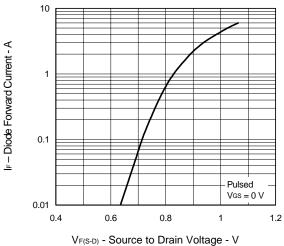
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



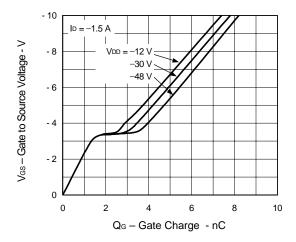
SWITCHING CHARACTERISTICS



SOURCE TO DRAIN DIODE FORWARD VOLTAGE



DYNAMIC INPUT/OUTPUT CHARACTERISTICS



[MEMO]

- The information in this document is current as of June, 2002. The information is subject to change
 without notice. For actual design-in, refer to the latest publications of NEC's data sheets or data
 books, etc., for the most up-to-date specifications of NEC semiconductor products. Not all products
 and/or types are available in every country. Please check with an NEC sales representative for
 availability and additional information.
- No part of this document may be copied or reproduced in any form or by any means without prior written consent of NEC. NEC assumes no responsibility for any errors that may appear in this document.
- NEC does not assume any liability for infringement of patents, copyrights or other intellectual property rights of third parties by or arising from the use of NEC semiconductor products listed in this document or any other liability arising from the use of such products. No license, express, implied or otherwise, is granted under any patents, copyrights or other intellectual property rights of NEC or others.
- Descriptions of circuits, software and other related information in this document are provided for illustrative
 purposes in semiconductor product operation and application examples. The incorporation of these
 circuits, software and information in the design of customer's equipment shall be done under the full
 responsibility of customer. NEC assumes no responsibility for any losses incurred by customers or third
 parties arising from the use of these circuits, software and information.
- While NEC endeavours to enhance the quality, reliability and safety of NEC semiconductor products, customers
 agree and acknowledge that the possibility of defects thereof cannot be eliminated entirely. To minimize
 risks of damage to property or injury (including death) to persons arising from defects in NEC
 semiconductor products, customers must incorporate sufficient safety measures in their design, such as
 redundancy, fire-containment, and anti-failure features.
- NEC semiconductor products are classified into the following three quality grades:
 - "Standard", "Special" and "Specific". The "Specific" quality grade applies only to semiconductor products developed based on a customer-designated "quality assurance program" for a specific application. The recommended applications of a semiconductor product depend on its quality grade, as indicated below. Customers must check the quality grade of each semiconductor product before using it in a particular application.
 - "Standard": Computers, office equipment, communications equipment, test and measurement equipment, audio and visual equipment, home electronic appliances, machine tools, personal electronic equipment and industrial robots
 - "Special": Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support)
 - "Specific": Aircraft, aerospace equipment, submersible repeaters, nuclear reactor control systems, life support systems and medical equipment for life support, etc.

The quality grade of NEC semiconductor products is "Standard" unless otherwise expressly specified in NEC's data sheets or data books, etc. If customers wish to use NEC semiconductor products in applications not intended by NEC, they must contact an NEC sales representative in advance to determine NEC's willingness to support a given application.

(Note)

- (1) "NEC" as used in this statement means NEC Corporation and also includes its majority-owned subsidiaries.
- (2) "NEC semiconductor products" means any semiconductor product developed or manufactured by or for NEC (as defined above).